Application No.: 10/006,704 Docket No.: M4065.0369/P369-A

## AMENDMENTS TO THE CLAIMS

This listing of claims replaces all prior listing of claims in this application.

Claims 1-25 (canceled).

26. (currently amended) A composition suitable for use in etching an insulative layer formed over a substrate in a semiconductor device, said composition comprising consisting of:

a flowing plasma etchant mixture consisting essentially of at least one fluorocarbon and ammonia, wherein the <u>a</u> flow rate ratio of each fluorocarbon to ammonia is from about 2:1 to about 40:1.

- 27. (previously presented) The composition of claim 26, wherein said fluorocarbon is at least one member selected from the group consisting of fluorohydrocarbons, chlorofluorocarbons and chlorofluorohydrocarbons.
- 28. (original) The composition of claim 27, wherein said fluorocarbon is at least one member selected from the group consisting of C₄F<sub>8</sub>, C₄F<sub>6</sub>, C₃F<sub>8</sub>, CF<sub>4</sub>, C₂F<sub>6</sub>, C₃F<sub>8</sub>, CHF₃, and CH₂F₂.
- 29. (original) The composition of claim 26, wherein said fluorocarbon is at least one member selected from the group consisting of CF<sub>4</sub>, CHF<sub>3</sub>, and CH<sub>2</sub>F<sub>2</sub>.
- 30. (original) The composition of claim 29, wherein said fluorocarbon is at least two members selected from the group consisting of CF<sub>4</sub>, CHF<sub>3</sub>, and CH<sub>2</sub>F<sub>2</sub>.
- 31. (original) The composition of claim 30, wherein said fluorocarbon is a combination of CF<sub>4</sub>, CHF<sub>3</sub>, and CH<sub>2</sub>F<sub>2</sub>.

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32. (previously presented) The composition of claim 26, wherein said composition is ineffective to remove side wall spacers of a gate stack formed over said substrate.

Claims 33-70 (canceled).

71. (currently amended) A composition suitable for use in etching an insulative layer formed on a substrate in a semiconductor device, said composition comprising consisting of:

a flowing plasma etchant mixture comprising at least consisting of at least two fluorocarbons CF4 and NH3, wherein the flow rate ratio of said CF4:NH3-is greater than about 3:1.

Claims 72-76 (canceled).

77. (new) A composition suitable for use in etching an insulative layer formed over a substrate in a semiconductor device, said composition consisting of:

a gaseous etchant mixture consisting of at least one fluorocarbon and ammonia.